

II. SPECIFICATION AMENDMENTS

Please amend the paragraph on page 1, lines 6-19 as follow:

Integrated Circuits (IC) generally need to be tested to assure proper operation. This - in particular - is required during IC development and manufacturing. In the latter case, the ICs are usually tested before final application. During test, the IC, as device under test (DUT), is exposed to various types of stimulus signals, and its responses are measured, processed and usually compared to an expected response of a good device. Automated test equipments (ATE) usually perform these tasks according to a device-specific test program. Examples for ATE are the Agilent 83000 and 93000 families of Semiconductor Test Systems of Agilent Technologies—as disclosed—e.g.—under http://www.ate.agilent.com/ste/products/intelligent_test/SOC_test/SOC_Tech_Overview.html. Details of those families are also disclosed e.g. in EP-A-859318, EP-A-864977, EP-A-886214, EP-A-882991, EP-A-1092983, US-A-5,499,248, US-A-5,453,995

Please amend the Abstract on page 14 as shown on the following page: